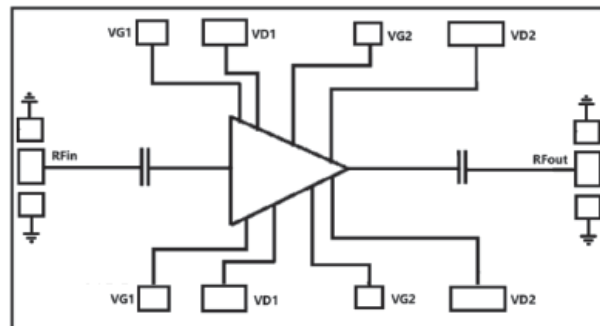


**Features**

- Frequency: 6.5-9GHz
- Gain: 24dB
- P1dB: 40dBm
- Psat: +41dBm
- PAE@Psat: 46%
- Power Supply: +8V@2A
- Input/Output: 50Ω
- Die Size: 5.27 x 5.3 mm

**Typical Applications**

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

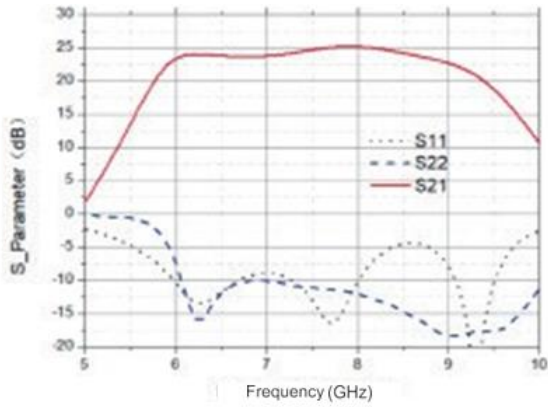
**Functional Block Diagram**

**Electrical Specifications**

TA = +25°C, Vdd = +8V (On-wafer Measurement Results)

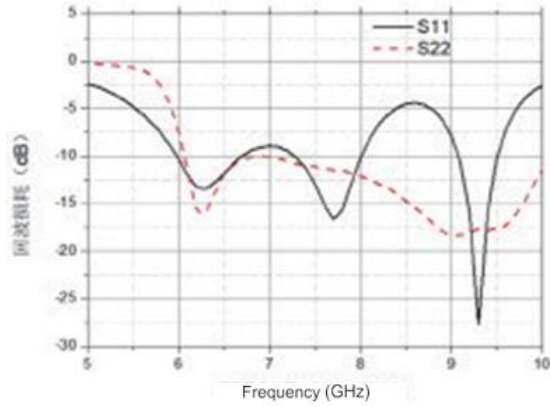
Parameters	Min.	Typ.	Max.	Units
Frequency	6.5-9			GHz
Gain		24		dB
P1dB		40		dBm
Psat		41		dBm
Input Return Loss		-12		dB
Output Return Loss		-15		dB
PAE		46		%
Operating Current		2		A



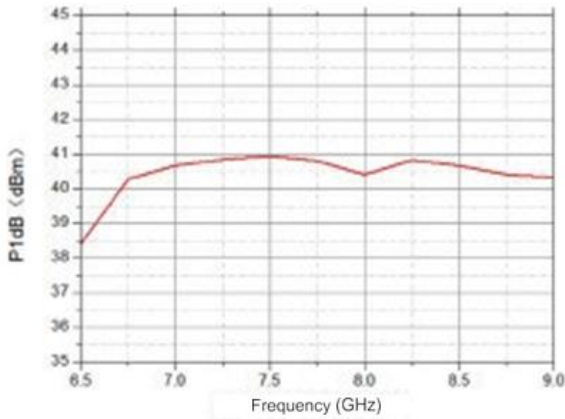
### S-Parameter vs. Frequency



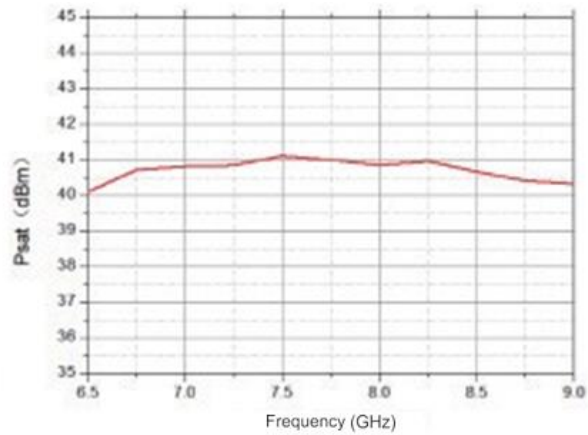
### I/O Return Loss vs. Frequency



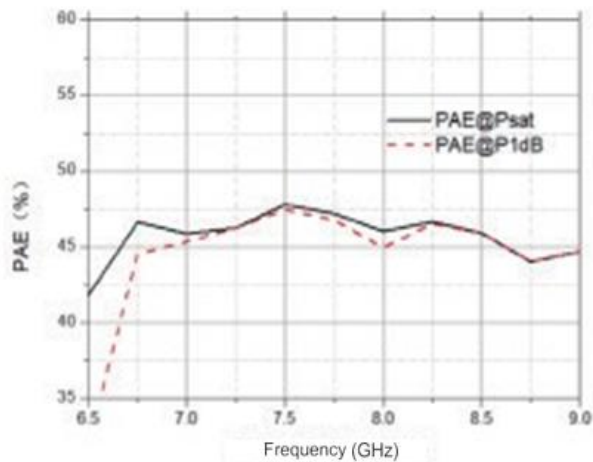
### P1dB vs. Frequency



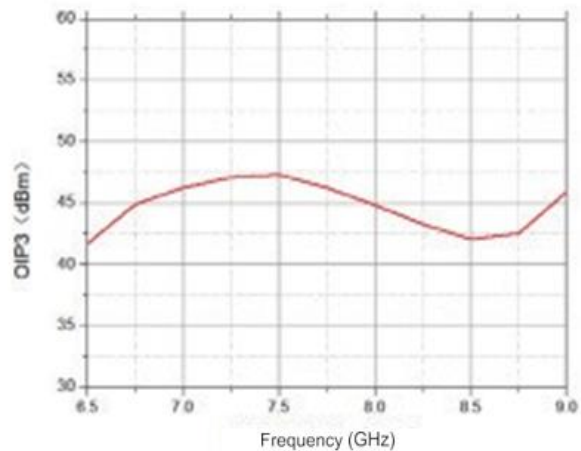
### Psat vs. Frequency



### PAE vs. Frequency

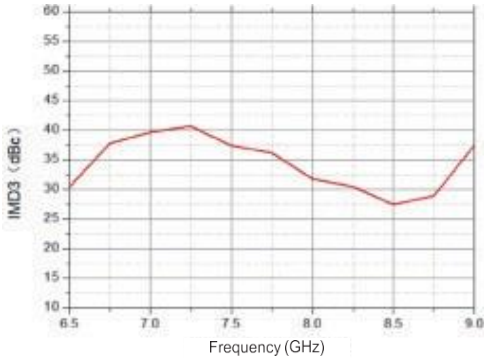


### OIP3 vs. Frequency

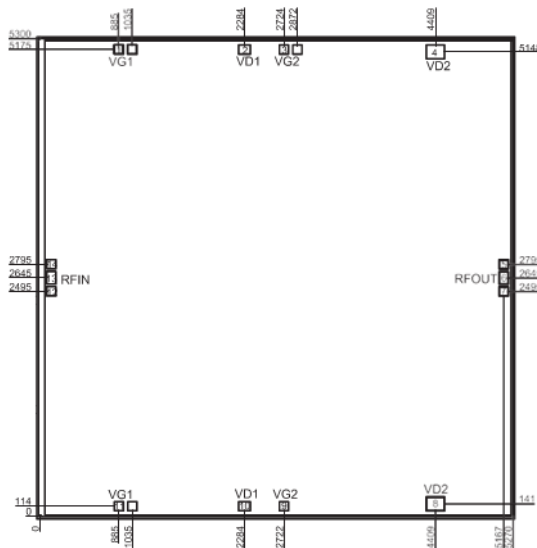




### IMD3 vs. Frequency



### Outline Drawing: All Dimensions in $\mu\text{m}$

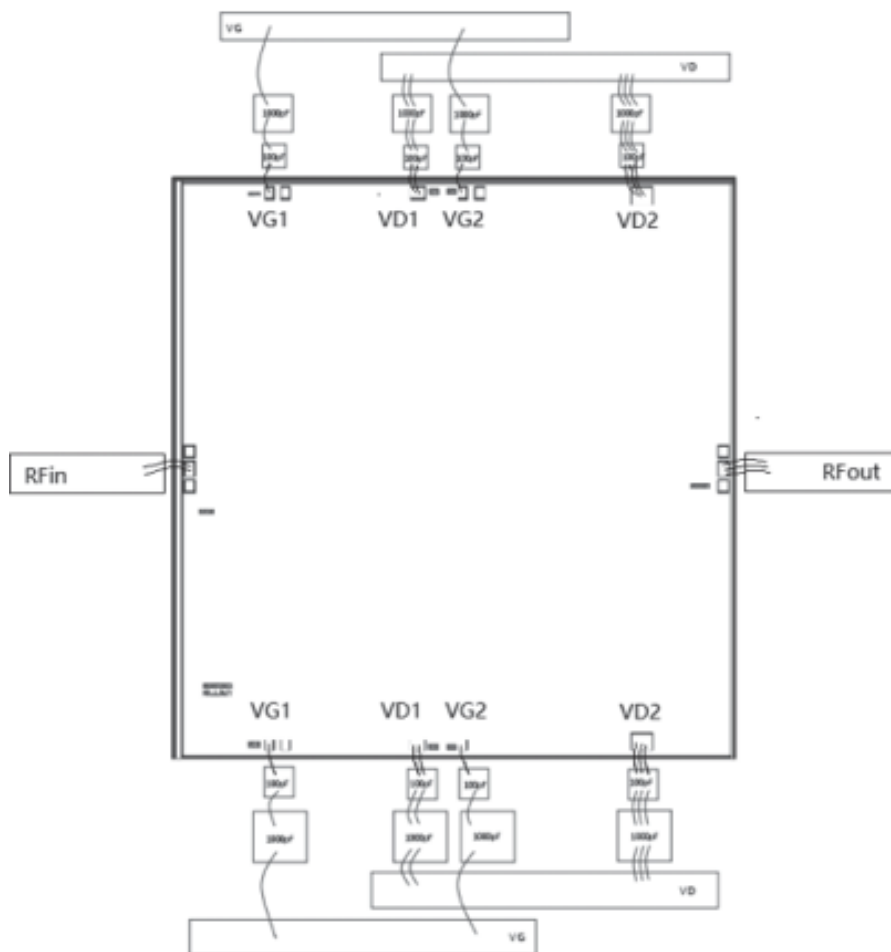


### Pad Description

Pad	Function	Description
13	RF IN	Signal input terminal, connected to 50 $\Omega$ circuit .
6	RF OUT	Signal output terminal, connected to 50 $\Omega$ circuit.
2,4,8,10	Vdd	Amplifier power supply; external 100pF capacitor required.
1,3,9,11	Vgg	Amplifier gate control power supply; external 100pF, 1000pF capacitor required.
5,7,12,14	GND	Die bottom must be connected to RF/DC ground.



### Assembly Drawing (Bond testing)



#### Notes:

1. Die thickness: 100um
2. Typical bond pad is 100\*100  $\mu\text{m}^2$
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

#### Maximum Ratings:

1. Supply voltage: +9V
2. RF Input power: +25dBm
3. Maximum input power: +25dBm
4. Operating temperature: -55°C to +85°C
5. Storage temperature: -65°C to +150°C